

Search Notes



Application/Control No.

09/577,225

Examiner

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Applicant(s)/Patent under Reexamination

LEWIS, LUNDY

Art Unit

3629

SEARCHED

Class	Subclass	Date	Examiner
705	1	2/06	DN
	7		
	8		
	9		
	10		
	26		
713	1		
	100		
709	200		
201	202		
370	252		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
I US patent PG Pub	2/06	DN
II FOREIGN EPO JPO Karent IBM-TDR		
III NPL		
Reviewing parent	2/06	DN